

DOCUMENT CHANGE REQUEST

512 DCR number Changes required for: General Originator: S Jeffery - ESCC Date: 2009/05/06 Organisation: ESA/ESTEC Date sent: 2009/05/06 Status: IMPLEMENTED Title: Transistors Low Power NPN, based on types 2N3498 thru 2N3501 2 Number: 5201/013 Issue: Other documents affected: Page: See attachment Paragraph: See attachment Original wording: Proposed wording: Update the Maximum Ratings table (see the attachment for details) so that this detail spec is clear, complete and the content and format is in-line with other detail specifications for similar Part Types. Justification: Improve the content and clarity of the spec. Attachments: 5201013_Issue_3_-_Draft_A.pdf, null Modifications: Page 6: Original Note 2 to Maximum Ratings – add ", and any handling," between "testing" and "performed". Approval signature: 12. (c f(an-9 Date signed: 2009-05-06

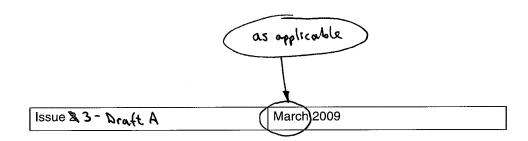


Pages 1 to 15

TRANSISTORS, LOW POWER, NPN

BASED ON TYPE 2N3501

ESCC Detail Specification No. 5201/013







ESCC Detail Specification No. 5201/013

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DOCUMENTATION CHANGE NOTICE

(Refer to https://escies.org for ESCC DCR content)

DCR N	о.	CHANGE DESCRIPTION
4 83	<u> </u>	Specification up issued to incorporate editorial and technical changes per DCR.
(tbd)

Characteristics	Symbols	Maximum Ratings	Unit	Remarks
Collector-Base Voltage	V _{CBO}	150	٧	Over entire operating temperature range
Collector-Emitter Voltage	V _{CEO}	150	٧	
Emitter-Base Voltage	V _{EBO}	6	٧	
Collector Current	I _C	300	mA	
Power Dissipation	P _{tot1}	1	W	At T _{amb} ≤ +25°C *Note*1)
	P _{tot2}	5	W	At T _{case} ≤ +25°C
Operating Temperature Range	T _{op}	-65 to +200	°C	Note 🍇 🚹
Storage Temperature Range	T _{stg}	-65 to +200	°C	Note 🕏 🕹
Soldering Temperature	T _{sol}	+260	°C	Note 💸 2

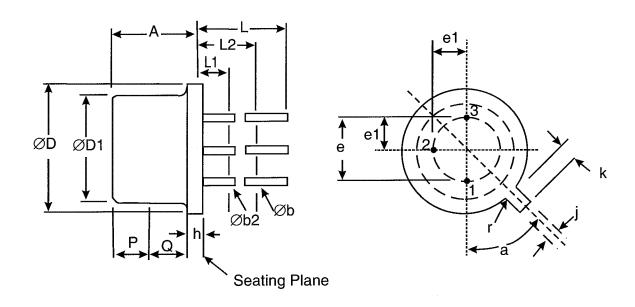
NOTES:

see attached

- 1. For Tamb or Tcase > +25°C, derate-linearly to 0W-at +200°C.
- For Variants with tin-lead plating or hot solder dip lead finish all testing performed at T_{amb} > +125°C shall be carried out in a 100% inert atmosphere.
- 2 Duration 10 seconds maximum at a distance of not less than 1.5mm from the device body and the same lead shall not be resoldered until 3 minutes have elapsed.

1.6 PHYSICAL DIMENSIONS AND TERMINAL IDENTIFICATION

1.6.1 Metal Can Package (TO-5) - 3 lead



Thermal Resistance,				
Junction-to-Ambient	R _{th(j-a)}	175	°C/W	
Thermal Resistance,				
Junction-to-Case	$R_{th(j-c)}$	35	°C/W	

, ,